

ABSTRACT OF THE DISCLOSURE

A unit which overlays first and second substrates, after the surfaces of the first and second substrates are cleaned and/or activated, is accommodated in a chamber, and the interior of the chamber is isolated from an outer space. In the chamber isolated from the outer space, the state of the surfaces of the first and second substrates is measured. The surfaces of the first and second substrates are cleaned on the basis of the measurement result. After that, the first and second substrates are overlaid.